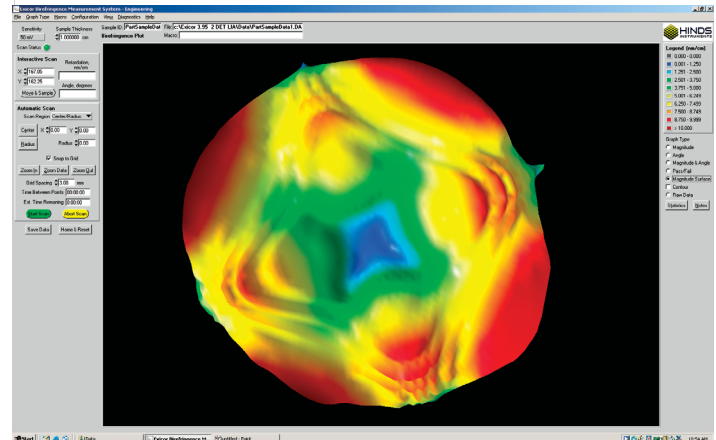


The new Exicor 120AT is versatile enough to excel in both production floor and R&D lab environments. The bench top design and intuitive automated scanning software make this product ideal for day-in-day-out evaluation of small parts (up to 120 mm x 100 mm).

The standard high speed scanning package, Scan in Motion™ or SIM, makes high spatial resolution scans (<1 mm grid spacing) practical.



Applications

- ♦ Quality control metrology
- ♦ Low-level birefringence measurements of
 - ♦ Plastic Films
 - ♦ Lens Blanks
 - ♦ Laser Crystals
 - ♦ Cell Phone Display Windows

Significant Features

- ♦ Unprecedented sensitivity in low-level birefringence measurement
- ♦ Simultaneous measurement of birefringence magnitude and angle
- ♦ Precision repeatability
- ♦ High-speed measurement
- ♦ No moving parts in the optical system
- ♦ Automatic mapping of variable-sized optical elements
- ♦ Simple, user-friendly operation

SPECIFICATIONS

Retardation Range:	0.005 to 300+ nm
Retardation Resolution /Repeatability ^{1, 2} :	0.001 nm / ± 0.02 nm
Angular Resolution /Repeatability ³ :	0.01° / $\pm 0.07^\circ$
Measurement Rate / Time ⁴ :	15 samples/sec (at 1nm spacing)
System Dimensions:	715 mm (H) x 350 mm (W) x 360 mm (D)
Light Source Wavelength ⁵ :	Various (633 nm standard)
Measurement Spot Diameter ⁶ :	Between 1 mm and 3 mm
Measurement Units:	nm (retardation), ° (angle)

1 Typical performance at 5 nm retardation

2 Up to 2nm, 1% thereafter

3 Typical performance at 10nm retardation

4 Maximum data collection speed. Sample XY scan time dependent on stage movement parameters.

5 Custom wavelengths available

6 Spot sizes of less than 1 mm require optional high resolution detector module

